

Application/Control No.		Applicant(s)/Patent under Reexamination	
09/749,921		O'DONNELL ET	ΓAL.
Examiner		Art Unit	
Binh X. Tran		1765	

	SEAR	CHED	
Class	Subclass	Date	Examiner
156	345.33	4/11/2005	BT
156	345.37	4/11/2005	5
156	345.47	4/11/2005	灯
156	345.51	4/11/2005	竹
156	345.52	4/11/2005	135

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	1				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
Update search using EAST	4/11/2005	B+	
